

The invention claimed is:

- Sub A¹
1. An RF probe, comprising:
 - 2 a conductive return;
 - 3 a insulating contact surface;
 - 4 a probe conductor positioned adjacent to the insulating contact surface; and
 - 5 a termination electrically positioned between the conductive return and the probe
 - 6 conductor.
 - Sub B²
 - 1 2. The RF probe of claim 1, wherein the conductive return is a ground return.
 3. The RF probe of claim 1, wherein the termination is a resistor.
 - Sub A²
 - 1 4. The RF probe of claim 3, wherein the termination is a resistor of approximately 50
 - 2 ohms.
 - Sub B⁴
 - 1 5. The RF probe of claim 1, wherein the termination is a semiconductor device.
 6. The RF probe of claim 5, wherein the termination is a diode.
 - Sub A³
 - 1 7. An RF probe, comprising:
 - 2 a conductive return;
 - 3 a probe conductor positioned within an insulator; and
 - 4 a termination electrically positioned between the conductive return and the probe
 - 5 conductor.
 - Sub B⁶
 - 1 8. The RF probe of claim 7, wherein the conductive return is a ground return.
 9. The RF probe of claim 7, wherein the termination is a resistor.
 - Sub A⁴
 - 1 10. The RF probe of claim 9, wherein the termination is a resistor of approximately 50
 - 2 ohms.
 - Sub B⁸
 - 1 11. The RF probe of claim 7, wherein the termination is a semiconductor device.

1 12. The RF probe of claim 11, wherein the termination is a diode.

Sub
B8
end
1 13. The RF probe of claim 7, wherein the insulator has at least a partial cross section that
2 is substantially circular in a plane substantially perpendicular to the probe conductor.

1 14. The RF probe of claim 13, wherein the conductive return is a ground return.

1 15. The RF probe of claim 13, wherein the termination is a resistor.

Sub A5
2 16. The RF probe of claim 15, wherein the termination is a resistor of approximately 50
ohms.

Sub
B10
1 17. The RF probe of claim 13, wherein the termination is a semiconductor device.

1 18. The RF probe of claim 17, wherein the termination is a diode.

Sub A6
2 19. An RF probe, comprising:
3 a conductive return;
4 a probe conductor positioned within an insulator, the probe conductor being curved and
5 the insulator having at least a partial cross section that is substantially circular in a plane
6 substantially perpendicular to the probe conductor; and
7 a termination electrically positioned between the conductive return and the probe
conductor.

Add A7